# MSKSEMI 美森科













**ESD** 

3

TSS

MOV

GDT

PLED

MS2308A

Product specification





## **Description**

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

BVDSS	RDSON	ID
60V	75mΩ	3A

#### **Features**

- 60V,3A, RDS(ON) =75mΩ@VGS = 10V
- Improved dv/dt capability
- Fast switching
- Green Device Available

## **Applications**

- Motor Drive
- Power Tools
- LED Lighting

#### **Reference News**

PACKAGE OUTLINE	N-Channel MOSFET	Marking
SOT-23	Go	A8***

# Absolute Maximum Ratings (T<sub>A</sub>=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
V <sub>D</sub> s	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
lo	Drain Current – Continuous (Tc=25℃)	3.0	А
Drain Current – Continuous (T <sub>C</sub> =100℃)		2	А
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	12.0	Α
Po	Power Dissipation (T <sub>C</sub> =25℃)	1.25	W
FD	Power Dissipation – Derate above 25℃	0.012	W/℃
T <sub>STG</sub>	Storage Temperature Range	-50 to 150	$^{\circ}$
TJ	Operating Junction Temperature Range	-50 to 125	$^{\circ}$

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Rеja	Thermal Resistance Junction to ambient		80	°C/W



# Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60			٧
∆ BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃,I <sub>D</sub> =1mA	1	0.05		V/°C
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =60V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	uA
IDSS	Drain-Oddice Leakage Guiterit	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =125℃			10	uA
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA

#### **On Characteristics**

R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS}$ =10 $V$ , $I_{D}$ =3 $A$		75	95	mΩ
T (DS(ON)	Static Drain-Source On-Nesistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =2A		85	110	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	-V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.0	1.6	2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient			-5		mV/℃
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =3A		7		S

**Dynamic and switching Characteristics** 

<u>- j</u>	a switching characterione			
$Q_g$	Total Gate Charge <sup>2, 3</sup>		 9.3	
Qgs	Gate-Source Charge <sup>2,3</sup>	$V_{DS}$ =48 $V$ , $V_{GS}$ =10 $V$ , $I_{D}$ =3 $A$	 2.1	 nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>		 1.8	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2 , 3</sup>		 2.9	
Tr	Rise Time <sup>2, 3</sup>	V <sub>DD</sub> =30V , V <sub>GS</sub> =10V ,	 9.5	
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2 , 3</sup>	R <sub>G</sub> =3.3Ω l <sub>D</sub> =1A	 18.4	 ns
Tf	Fall Time <sup>2,3</sup>		 5.3	
C <sub>iss</sub>	Input Capacitance		 500	
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , F=1MHz	 45	 pF
Crss	Reverse Transfer Capacitance		 16	
Rg	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, F=1MHz	 2	 Ω

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	\/ -\/ -0\/   Fares Current			3.0	Α
Іѕм	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			6.0	Α
Vsp	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25℃			1.2	V

#### Note

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed, pulse width  $\leq$  300 us, duty cycle  $\leq$  2%.
- 3. Essentially independent of operating temperature.



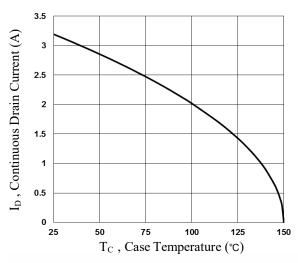


Fig.1 Continuous Drain Current vs. Tc

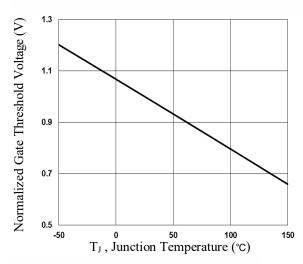


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

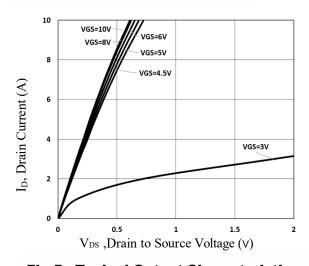


Fig.5 Typical Output Characteristics

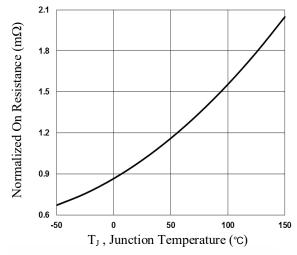


Fig.2 Normalized RDSON vs. T<sub>J</sub>

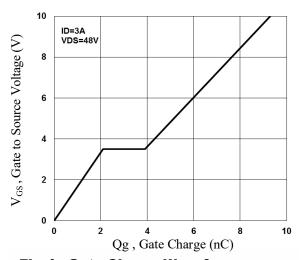


Fig.4 Gate Charge Waveform

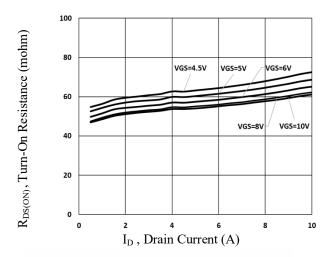


Fig.6 Turn-On Resistance vs. ID

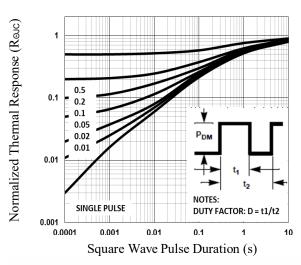


Fig.7 Normalized Transient Response

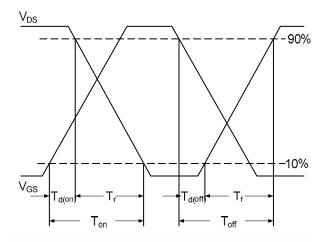


Fig.9 Switching Time Waveform

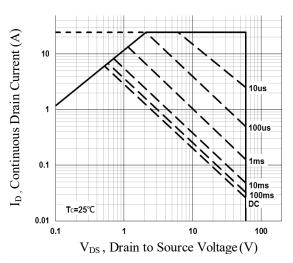
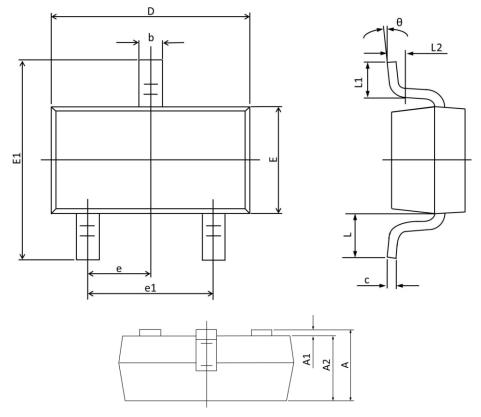


Fig.8 Maximum Safe Operation Area



## **SOT-23 PACKAGE INFORMATION**



Symbol	<b>Dimensions In Millimeters</b>		Dimension	s In Inches
Symbol	Max	Min	Max	Min
A	1.150	0.900	0.045	0.035
A1	0.100	0.000	0.004	0.000
A2	1.050	0.900	0.041	0.035
b	0.500	0.300	0.020	0.012
c	0.150	0.080	0.006	0.003
D	3.000	2.800	0.118	0.110
E	1.400	1.200	0.055	0.047
E1	2.550	2.250	0.100	0.089
e	0.95	TYP.	0.03	7 TYP.
e1	2.000	1.800	0.079	0.071
L	0.55 REF.		0.022	2 REF.
L1	0.500	0.300	0.020	0.012
L2	0.25 TYP.		0.01	TYP.
θ	<b>8</b> °	0°	<b>8</b> °	<b>0</b> °

# **REELSPECIFICATION**

P/N	PKG	QTY
MS2308A	SOT-23	3000



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